

FCAL: Status Report: (FEE)

M. Idzik for FCAL Collaboration

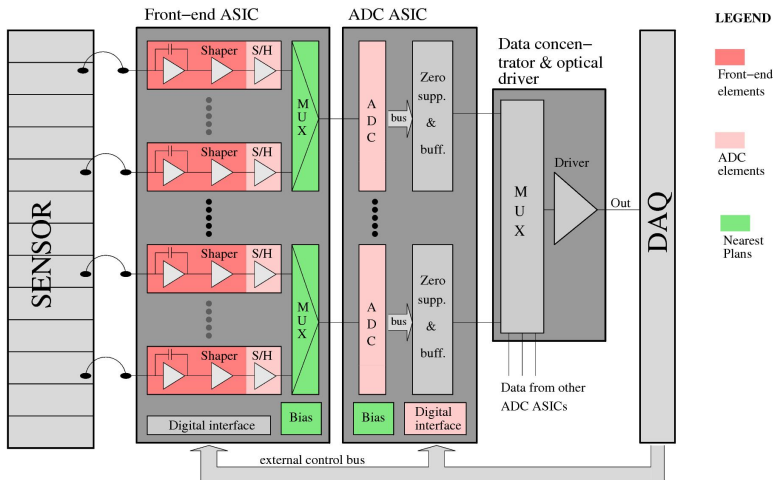
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EUDET SC-meeting 31 August 2009

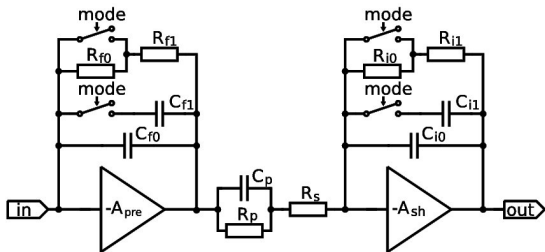
Outline

- 1 Front-End development
- 2 Development of 10 bit ADC
- 3 Peripheral circuits
- 4 Digital processing and data concentrator
- 5 Full chain Test setup (beam) preparation
- 6 Summary

LumiCal Readout System



Front-end requirements (old)



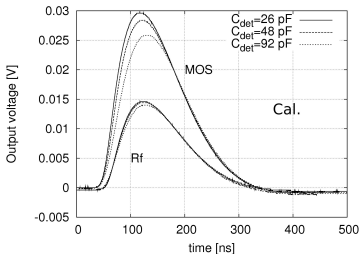
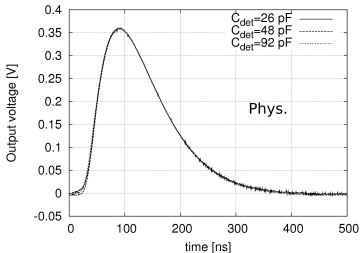
Components

- Charge amplifier
- Pole zero cancellation
- 1st order shaper

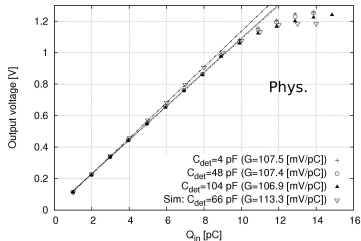
- $C_{det} = 10 \div 100 \text{ pF} \rightarrow$ charge sensitive amplifier
- $\Delta t \simeq 300 \text{ ns} \rightarrow T_{peak} \simeq 60 \text{ ns}$
- Two independent modes: physics and calibration (MIP)
 \rightarrow gain switched as a configuration option
- Physics mode: $Q_{max} \approx 10 \text{ pC} \rightarrow C_f \approx 10 \text{ pF}$
- Calibration mode: $S/N > 10$ for MIP

Example pulse shape and linearity

Pulse shape



Gain



- For physics mode
 $Q_{in} = 3.3$ pC (upper left)
- In calibration $Q_{in} \approx 10$ fC (left)
- Linear up to 10 pC

Front-end parameters summary

Mode	Gain [mV/fC]	Noise@50pF [fC]	Linearity [pC]	Rate [MHz]	Crosstalk [%]
Physics	0.107	0.62	10	3	≈ 1
Calibration	≈ 20	0.28	0.035	2.5	≈ 0.1

- Similar results for both R_F and MOS configurations (MOS slightly better)
- Crosstalk needs to be measured with sensor fanout
- Power consumption per channel is 8.9 mW
- Noise in details:
 - $\text{Noise}_{\text{phys}}[\text{aC}] = 522 + 2.08 \cdot C_{in}[\text{pF}]$
 - $\text{Noise}_{\text{cal}}[\text{aC}] = 48 + 4.65 \cdot C_{in}[\text{pF}]$

Front-end status and future plans

● Status

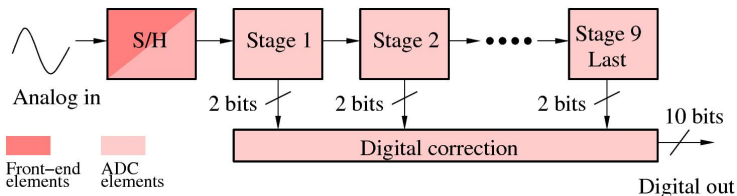
- First prototype tested and ready for tests with sensor
- Single prototype ASIC comprises of 8 channels
- Parameters meet specifications

● Future plans

- Tests with sensor and fanout
- Measurements on test beam
- Will we need new prototype ?, are there still some parameters to be fixed ? (Switching on/off needs to be added)

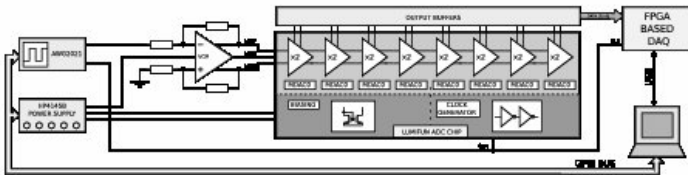
M. Idzik, Sz. Kulis, D. Przyborowski, "Development of front-end electronics for the luminoisty detector at ILC" Nucl. Instr. and Meth. A 608 (2009) pp.169-174

ADC Requirements

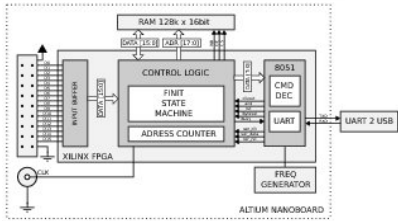


- Speed or clock frequency
 - 3MHz when one ADC per channel ← *most probable conf.*
 - 30MHz when one ADC per ~8 channels
- 10 bits at the moment
- Power efficient & small area
- Fully differential pipeline architecture
- S/H can be a part of ADC or front-end channel → two prototypes with and without S/H designed

ADC Test Setup



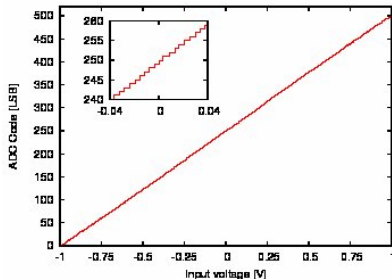
- Signal from AWG2021 generator
- External single-ended to differential converter
- Software digital correction (first prototype)
- FPGA based (Altium nanoboard with Xilinx Spartan2E) DAQ



FPGA based DAQ

ADC - First prototype

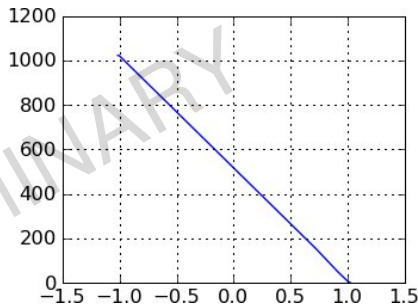
- Only 8 pipeline stages
- No digital correction
- Fully functional
- Works up to 35 MHz
- max INL < 3 LSB
- max DNL=-1 (few missing codes)



M. Idzik, K. Swientek, S. Kulis, "Development of Pipeline ADC for the Luminosity Detector at ILC", Proc. 15th Int. Conf. "Mixed Design of Integrated Circuits and Systems" MIXDES 2008, Poznan, Poland, 19-21 June 2008, IEEE Xplore database

ADC - Second prototype

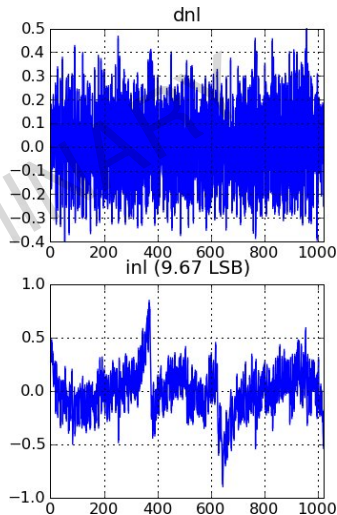
- All 9 stages + S/H
- Digital correction
- Clock and power switching
- No reference voltages yet
- Fully functional



M. Idzik, K. Swientek, S. Kulis, "Design and measurements of 10 bit pipeline ADC for the Luminosity Detector at ILC", will be presented at TWEPP2009, Paris september 21-25 2009, <http://twepp09.lal.in2p3.fr>

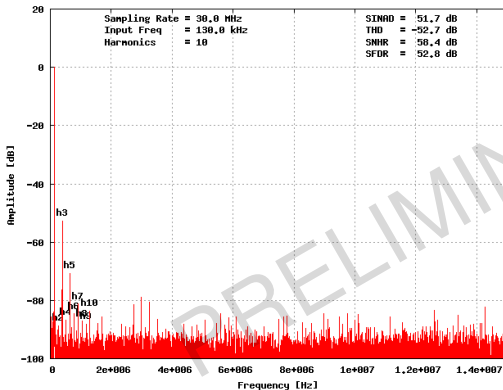
ADC - Second prototype - linearity

- Good INL ($<1\text{LSB}$)
- Good DNL ($<0.5\text{LSB}$)
- Works up to 35 MHz



Dynamic measurements 30 MHz

FFT spectre



- SINAD = 51.7 dB
- THD = -52.7 dB
- SNHR = 58.4 dB (9.4 bits)
- SFDR = 52.8 dB

- Very preliminary, first measurements
- SNHR (noise) is good
- SINAD affected by harmonic distortions which may come from setup; pure differential sine signal generator needed.

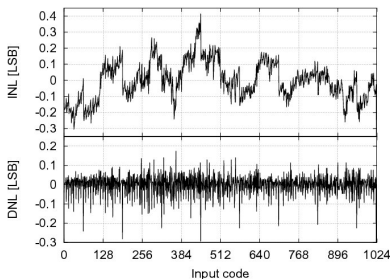
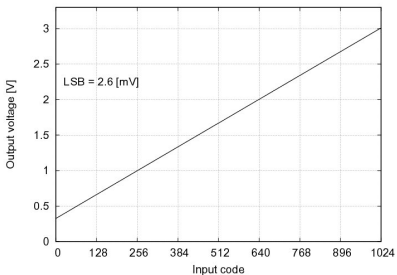
ADC summary and future plans

- Summary
 - New 10-bit ADC prototypes are fully functional
 - They work up to about 35 MHz as expected
 - Static measurements show good DNL, INL & ENOB
 - Dynamic measurements need setup improvements
 - Power consumption can be scaled with frequency
- Future plans
 - Measurements
 - Continue static and power measurements
 - Precise dynamic measurements
 - Clock and power switching tests
 - Prepare multichannel version

10 bit general purpose DAC design

- Designed, fabricated and tested
- Fully functional
- High-swing voltage output
- Core area 0.18 mm^2
- Power cons. $< 0.6 \text{ mW}$
- max INL $< 0.42 \text{ LSB}$
- max DNL $< 0.42 \text{ LSB}$

D. Przyborowski, M. Idzik, "Development of a General Purpose Low-power Small-area 10 bit Current Steering CMOS DAC", Proc. 15th Int. Conf. "Mixed Design of Integrated Circuits and Systems" MIXDES 2009, Lodz, Poland, 25-27 June 2009, IEEE Xplore database



Other designs

- Bandgap reference voltage designed and fabricated, to be tested
- Fast (>500 MHz) LVDS transmitter and receiver designed and fabricated, to be tested

Digital processing & data concentrator

- Waiting for better detector specification → data flux
- Pure digital design so can be done fast in comparison to front-end and ADC
- Will first be designed and tested with FPGA
- After FPGA tests ASIC implementation should be fast (month or two)

Test setup (beam) preparation

- Silicon sensors from Hamamatsu ready and preliminary I-V and C-V measurements performed
- First fanout structures designed and fabricated
- Prototype front-end (8 channels) ASICs will be used
- External ADC will be used since the prototype ADC ASIC is not yet multichannel
- PCB board for test setup designed and produced

Summary

- Front-end prototype ready for test beam
- New almost complete ADC prototype under tests, preliminary results promising
- Peripheral circuits (DAC, Bandgap, LVDS) designed, fabricated and partially tested
- Data concentrator will be first implemented as FPGA circuit, so no need for ASIC prototyping
- Full chain Test setup (beam) preparation in progress